

Notice of References Cited	Application/Control No. 10/023,123	Applicant(s)/Patent Under Reexamination FUJITA ET AL.	
	Examiner Jacob Meek	Art Unit 2637	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0009169	01-2002	Watanabe, Takayuki	375/371
	B	US-2002/0044618 A1	04-2002	Buchwald et al.	375/371
	C	US-2002/0048335 A1	04-2002	Saeki, Yuji	375/371
	D	US-6,552,619	04-2003	Shastri, Kal	331/25
	E	US-6,636,993 B1	10-2003	Koyanagi et al.	714/700
	F	US-6,700,942 B1	03-2004	Lai, Benny W. H.	375/354
	G	US-6,813,724 B2	11-2004	Saito, Tatsuya	713/401
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.